

Date:

#### Product Change Notification / KSRA-18BGHS695

30-Sep-2021
Product Category:
Memory
PCN Type:
Manufacturing Change
Notification Subject:
CCB 4559 Final Notice: Qualification of SIGN as a new assembly site for selected SST39LFxxxx and SST39VFxxxx device families available in 48L TSOP (12x20mm) package.
Affected CPNs:
KSRA-18BGHS695_Affected_CPN_09302021.pdf KSRA-18BGHS695_Affected_CPN_09302021.csv
Notification Text:
PCN Status:
Final notification
PCN Type:  Manufacturing Change
PCN Type:
PCN Type: Manufacturing Change  Microchip Parts Affected:
PCN Type: Manufacturing Change  Microchip Parts Affected: Please open one of the icons found in the Affected CPNs section.

Assembled at LPI using 8340 die attach material and lead frame with paddle size 207x142mils, 183x161mils or 160x130mils.

#### **Post Change:**

Assembled at SIGN using AP-4300 die attach material and lead frame with paddle size 209x165mils or 159x165mils

#### **Pre and Post Change Summary:**

		Pre Change		Post Change				
Assembly Site	Lingsen Precision Industries, LTD. (LPI)			Signetics Corporation (SIGN)				
Bond Wire material		Au		Au				
Die Attach material		8340		AP-4300				
Mold compound material		G700		G700				
Lead frame material		C7025		C7025				
DAP Surface Prep		Ring/Selective		Ring/Selective				
Lood from a modello sino	207x142mils	183x161mils	160x130mils	s 209x165mils 159x165n				
Lead frame paddle size		See a	ttached pre and	post change comparison				

#### Impacts to Data Sheet:

None

#### **Change Impact:**

None

#### **Reason for Change:**

To improve on-time delivery performance by qualifying SIGN as a new assembly site.

#### **Change Implementation Status:**

In Progress

#### **Estimated First Ship Date:**

October 31, 2021 (date code: 2145)

NOTE: Please be advised that after the estimated first ship date customers may receive pre and post change parts.

#### **Time Table Summary:**

	February 2021			>	September 2021			October 2021								
Workweek	06	07	08	09	10		36	37	38	39	40	41	42	43	44	45
Initial PCN Issue Date				х												
Qual Report Availability											Х					
Final PCN Issue Date											Х					

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Estimated							l		
Implementation Date									^

#### Method to Identify Change:

Traceability code

#### **Qualification Report:**

Please open the attachments included with this PCN labeled as PCN\_#\_Qual\_Report.

#### **Revision History:**

February 23, 2021: Issued initial notification.

**April 14, 2021:** Re-issued initial notification to change die attach material to AP-4300 in pre and post change and qual plan. **September 30, 2021:** Issued final notification. Updated the lead frame DAP Surface Prep pre and post change to Ring/Selective. Attached the qualification report. Provided estimated first ship date to be on October 31, 2021.

The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable products.

#### **Attachments:**

PCN\_KSRA-18BGHS695\_Qual\_Report.pdf PCN\_KSRA-18BGHS695\_Pre and Post Change\_Summary.pdf

Please contact your local Microchip sales office with questions or concerns regarding this notification.

#### **Terms and Conditions:**

If you wish to <u>receive Microchip PCNs via email</u> please register for our PCN email service at our <u>PCN</u> home page select register then fill in the required fields. You will find instructions about registering for Microchips PCN email service in the <u>PCN FAQ</u> section.

If you wish to <u>change your PCN profile, including opt out,</u> please go to the <u>PCN home page</u> select login and sign into your myMicrochip account. Select a profile option from the left navigation bar and make the applicable selections.

KSRA-18BGHS695 - CCB 4559 Final Notice: Qualification of SIGN as a new assembly site for selected SST39LFxxxx and SST39VFxxxx device families available in 48L TSOP (12x20mm) package.

#### Affected Catalog Part Numbers (CPN)

SST39LF400A-55-4C-EKE

SST39VF400A-70-4C-EKE

SST39VF400A-70-4I-EKE

SST39LF400A-55-4C-EKE-T

SST39VF400A-70-4C-EKE-T

SST39VF400A-70-4I-EKE-T

SST39LF800A-55-4C-EKE

SST39VF800A-70-4C-EKE

SST39VF800A-70-4I-EKE

SST39VF800A-70-4I-EKE-TZ009

SST39VF800A-70-4C-EKE-T

SST39VF800A-70-4I-EKE-T

SST39VF1601-70-4C-EKE

SST39VF1602-70-4C-EKE

SST39VF1681-70-4C-EKE

SST39VF1682-70-4C-EKE

SST39VF1601-70-4C-EKE-PP013

SST39VF1601-70-4I-EKE

SST39VF1602-70-4I-EKE

SST39VF1681-70-4I-EKE

SST39VF1682-70-4I-EKE

SST39VF1601-70-4I-EKE-TZ009

SST39VF1601-70-4C-EKE-T

SST39VF1602-70-4C-EKE-T

SST39VF1681-70-4C-EKE-T

SST39VF1682-70-4C-EKE-T

SST39VF1601-70-4I-EKE-T

SST39VF1602-70-4I-EKE-T

SST39VF1681-70-4I-EKE-T

SST39LF200A-55-4C-EKE

SST39VF200A-70-4C-EKE

SST39VF200A-70-4I-EKE

SST39LF200A-55-4C-EKE-T

SST39VF200A-70-4C-EKE-T

SST39VF200A-70-4I-EKE-T

SST39VF3201B-70-4C-EKE

SST39VF3202B-70-4C-EKE

SST39VF3201B-70-4I-EKE

SST39VF3202B-70-4I-EKE

SST39VF3201B-70-4I-EKE-MCL

SST39VF3202B-70-4I-EKE-MCM

SST39VF3201B-70-4I-EKE-T

Date: Thursday, September 30, 2021

# CCB 4559 Pre and Post Change Summary PCN # KSRA-18BGHS695



A Leading Provider of Smart, Connected and Secure Embedded Control Solutions



### **Lead frame Comparison**

## **Pre Change Post Change** LPI **SIGN**





### QUALIFICATION REPORT SUMMARY RELIABILITY LABORATORY

**PCN #: KSRA-18BGHS695** 

Date September 21, 2021

Qualification of SIGN as a new assembly site for selected SST39LFxxxx and SST39VFxxxx device families available in 48L TSOP (12x20mm) package.



Purpose Qualification of SIGN as a new assembly site for selected

SST39LFxxxx and SST39VFxxxx device families available in 48L

TSOP (12x20mm) package.

**CCB No.** 4559

**CN** ES358575

**QUAL ID** R2100642 Rev. A **MP CODE** X02057W9XM70

Part No. SST39VF3201B-70-4I-EKE

Bonding No. BDM-002852 Rev. B

**Package** 

Type 48L TSOP
Package size 12 x 20 mm

**Lead Frame** 

Paddle size 209 x 165 mils

Material C7025

Surface Ring / Selective Plating

Process Stamped

Lead Lock No

Part Number FLF-00001
Treatment Roughened

<u>Material</u>

Epoxy AP-4300
Wire Au wire
Mold Compound G700
Plating Composition Matte Sn



#### **Manufacturing Information**

Assembly Lot No.	Wafer Lot No.	Date Code		
SIGN220200003.000	GC01919127814.100	2114KGK		
SIGN220200004.000	GC01920463252.000	2114KGT		
SIGN220200005.000	GC01921068944.000	2114KGV		

Result	X Pass	Fail		
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48L TSOP (12x20 mm) assembled by SIGN pass reliability test per QCI-39000. This package was qualified the Moisture/Reflow Sensitivity Classification Level 3 at 260°C reflow temperature per IPC/JEDEC J-STD-020E standard.

PACKAGE QUALIFICATION REPORT									
Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS	Result	Remarks			
Precondition Prior Perform	Electrical Test: +25°C, 95°C and -40°C System: NEXTEST_GV2X	JESD22- A113	693(0)	693		Good Devices			
Reliability Tests (At MSL Level 3)	Bake 150°C, 24 hrs System: CHINEE	JIP/ IPC/JEDEC		693					
	30°C/60%RH Moisture Soak 192 hrs. System: TABAI ESPEC Model PR-3SPH	J-STD-020E		693					
	3x Convection-Reflow 265°C max System: Vitronics Soltec MR1243			693					
	Electrical Test: +25°C and 95°C System: NEXTEST_GV2X			0/693	Pass				

	PACKAGE QUALIFICA	ATION	REP	ORT		
Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks
Temp Cycle	Stress Condition: -65°C to +150°C, 500 Cycles System: TABAI ESPEC TSA-70H Electrical Test: +95°C System: NEXTEST_GV2X	JESD22- A104	231(0)	231 0/231	Pass	Parts had been pre-conditioned at 260°C 77 units / lot
	Bond Strength: Wire Pull (> 2.5 grams) Bond Shear (>15.00 grams)		15 (0) 15 (0)	0/15 0/15	Pass Pass	
	Stress Condition: +130°C/85%RH, 96 hrs. System: HAST 6000X	JESD22- A118		231		Parts had been pre-conditioned at 260°C
UNBIASED-HAST	Electrical Test: +25°C System: NEXTEST_GV2X		231(0)	0/231	Pass	77 units / lot
	Stress Condition: +130°C/85%RH, 96 hrs. Bias Volt: 3.6 Volts System: HAST 6000X	JESD22- A110		231		Parts had been pre-conditioned at 260°C
HAST	Electrical Test: +25°C and 95°C System: NEXTEST_GV2X		231(0)	0/231	Pass	77 units / lot

PACKAGE QUALIFICATION REPORT										
Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks				
High Temperature Storage Life	Stress Condition: Bake 175°C, 504 hrs System: SHEL LAB	JESD22- A103		45		45 units				
	Electrical Test: +25°C and 95°C System: NEXTEST_GV2X		45(0)	0/45	Pass					
Solderability	Steam Aging: Temp 93°C,8Hrs System: SAS-3000	J-STD-002	22 (0)	22						
Temp 245°C	Solder Dipping: Solder Temp.245°C			22						
	Solder material: Pb Free Sn 95.5Ag3.9 Cu0.6System: ERSA RA 2200D Visual Inspection: External Visual Inspection			0/22	Pass					
Physical	Physical Dimension,	JESD22-	30(0)	0/30	Pass					
Dimensions	10 units from 1 lot	B100/B108	Units							
Bond Strength	Wire Pull (> 3.00 grams)	Mil. Std. 883-2011	30 (0) Wires	0/30	Pass					
Data Assembly	Bond Shear (> 10.00 grams)	CDF-AEC- Q100-001	30 (0) bonds	0/30	Pass					